

ABSTRACT

There is provided a current measuring method comprising the steps of: converting a current to be measured into a voltage signal; phase modulating light being transmitted through an optical modulator by the voltage signal; causing the phase modulated light to interfere with not phase modulated light to obtain interference light; and measuring the current to be measured depending upon the intensity of the interference light. In addition, there is provided an IC testing apparatus which measures a current flowing to a power supply terminal of an IC under test utilizing the above current measuring method, and when the measured current value is larger than a prescribed value, renders a decision that the IC under test is defective.